



FEATURES

- 2-MHz Sample Rate
- 16-Bit NMC Ensured Over Temperature
- Zero Latency
- Unipolar Differential Input Range: V_{ref} to -V_{ref}
- Onboard Reference
- Onboard Reference Buffer
- High-Speed Parallel Interface
- Power Dissipation: 175 mW at 2 MHz Typ
- Wide Digital Supply
- 8-/16-Bit Bus Transfer
- 48-Pin TQFP Package
- ESD Sensitive HBM Capability of 500 V, 1000 V at All Input Pins

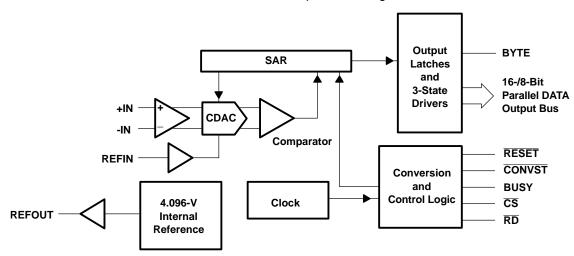
APPLICATIONS

- DWDM
- Instrumentation
- High-Speed, High-Resolution, Zero Latency Data Acquisition Systems
- Transducer Interface
- Medical Instruments
- Communication

DESCRIPTION

The ADS8412 is a 16-bit, 2 MHz A/D converter with an internal 4.096-V reference. The device includes a 16-bit capacitor-based SAR A/D converter with inherent sample and hold. The ADS8412 offers a full 16-bit interface and an 8-bit option where data is read using two 8-bit read cycles.

The ADS8412 has a unipolar differential input. It is available in a 48-lead TQFP package and is characterized over the industrial -40°C to 85°C temperature range.





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

ORDERING INFORMATION⁽¹⁾

MODEL	MAXIMUM INTEGRAL LINEARITY (LSB)	MAXIMUM DIFFERENTIAL LINEARITY (LSB)	NO MISSING CODES RESOLUTION (BIT)	PACKAGE TYPE	PACKAGE DESIGNATOR	TEMPERATURE RANGE	ORDERING INFORMATION	TRANSPORT MEDIA QUANTITY
ADS8412I	48 Pin DED			DEB 40°C to 85	–40°C to 85°C	ADS8412IPFBT	Tape and reel 250	
AD304121	−6 ~ 6	-2~+3	15	TQFP	FFB	-40 C to 65 C	ADS8412IPFBR	Tape and reel 1000
ADS8412IB	B -2.5 ~ 2.5		PFB	4000 4 0500	ADS8412IBPFBT	Tape and reel 250		
AD304121B	-2.5 ~ 2.5	−1~+2	16	TQFP	FFB	−40°C to 85°C	ADS8412IBPFBR	Tape and reel 1000

⁽¹⁾ For the most current specifications and package information, refer to our website at www.ti.com.

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range unless otherwise noted(1)

			UNIT	
Valtana	+IN to AGND		-0.4 V to +VA + 0.1 V	
Voltage	-IN to AGND		-0.4 V to +VA + 0.1 V	
	+VA to AGND		–0.3 V to 7 V	
Voltage range	+VBD to BDGND		-0.3 V to 7 V	
	+VA to +VBD		–0.3 V to 2.55 V	
Digital input voltage	ge to BDGND		-0.3 V to +VBD + 0.3 V	
Digital output volta	age to BDGND		-0.3 V to +VBD + 0.3 V	
Operating free-air	temperature range,	, T _A	-40°C to 85°C	
Storage temperati	ure range, T _{stg}		−65°C to 150°C	
Junction temperat	ure (T _J max)		150°C	
TOED	Power dissipation	1	(T _J Max - T _A)/θ _{JA}	
TQFP package	θ _{JA} thermal imped	dance	86°C/W	
		Vapor phase (60 sec)	215°C	
Lead temperature, soldering		Infrared (15 sec)	220°C	

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



SPECIFICATIONS

 $T_A = -40$ °C to 85 °C, +VA = 5 V, +VBD = 3 V or 5 V, $V_{ref} = 4.096$ V, $f_{SAMPLE} = 2$ MHz (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT		
ANALO	G INPUT		ı	1		-			
	Full-scale input voltage ⁽¹)	+IN - (-IN)	-V _{ref}		V_{ref}	V		
					+IN	-0.2		V _{ref} + 0.2	\/
	Absolute input voltage	bsolute input voltage		-0.2		V _{ref} + 0.2	V		
	Common-mode input range	ADS8412I		(V _{ref} /2) - 0.2	V _{ref} /2	$(V_{ref}/2) + 0.2$	V		
	Input capacitance				25		pF		
	Input leakage current				0.5		nA		
SYSTEM	M PERFORMANCE								
	Resolution				16		Bits		
-	Nie odada sa da	ADS8412I		15			D:1-		
	No missing codes	ADS8412IB		16			Bits		
		ADS8412I		-6	±4	6			
INL	Integral linearity (2)(3)	ADS8412IB		-2.5	±1.5	2.5	LSB		
		ADS8412I		-2	±1	3			
DNL	Differential linearity	ADS8412IB		-1	±0.8	2	LSB		
		ADS8412I		-3	±1	3	mV		
Eo	Offset error (4)	ADS8412IB		-1.5	±0.5	1.5			
		ADS8412I		-0.15		0.15	%FS		
E_G	Gain error ⁽⁴⁾⁽⁵⁾	ADS8412IB		-0.098		0.098			
			At dc (±0.2 V around V _{ref} /2)		80				
CMRR	Common-mode rejection	ratio	+IN - (-IN) = 1 V _{pp} at 1 MHz		80		dB		
	Noise		, γ ρρ		60		μV RMS		
PSRR	DC Power supply rejection	on ratio	At 7FFFh output code, +VA = 4.75 V to 5.25 V, Vref = 4.096 V (4)		1		LSB		
SAMPLI	ING DYNAMICS								
	Conversion time			340		400	ns		
	Acquisition time			100			ns		
	Throughput rate					2	MHz		
	Aperture delay				2		ns		
	Aperture jitter				25		ps		
	Step response				100		ns		
	Overvoltage recovery				100		ns		
DYNAM	IC CHARACTERISTICS			I.					
TUD	THD Total harmonic distortion (6)		$V_{IN} = 8 V_{pp}$ at 100 kHz		-95		٦D		
IHD			$V_{IN} = 8 V_{pp}$ at 500 kHz		-90		dB		
SNR	Signal-to-noise ratio		$V_{IN} = 8 V_{pp}$ at 100 kHz		90		dD		
SINAD	Signal-to-noise + distorti	on	$V_{IN} = 8 V_{pp}$ at 100 kHz		88		dB		
٥٥٥٥	On whom for the sail		$V_{IN} = 8 V_{pp}$ at 100 kHz		95		, ID		
SFDR	Spurious free dynamic ra	ange	$V_{IN} = 8 V_{pp}$ at 500 kHz		93		dB		
	-3 dB Small signal band	width			5		MHz		

- Ideal input span, does not include gain or offset error.
- LSB means least significant bit
- (3)
- This is endpoint INL, not best fit

 Measured relative to an ideal full-scale input [+IN (-IN)] of 8.192 V
- This specification does not include the internal reference voltage error and drift. (5)
- (6) Calculated on the first nine harmonics of the input frequency



SPECIFICATIONS (continued)

 $T_A = -40$ °C to 85°C, +VA = 5 V, +VBD = 3 V or 5 V, $V_{ref} = 4.096$ V, $f_{SAMPLE} = 2$ MHz (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
EXTE	RNAL VOLTAGE REFEREN	CE INPUT					
V_{ref}	Reference voltage at REI	FIN		3.9	4.096	4.2	V
	Reference resistance ⁽⁷⁾				500		kΩ
INTER	RNAL REFERENCE OUTPUT	Γ					
	Internal reference start-u	p time	From 95% (+VA), with 1 µF storage capacity			120	ms
V_{ref}	Reference voltage		IOUT = 0	4.065	4.096	4.13	V
	Source current		Static load			10	μΑ
	Line regulation		+VA = 4.75 ~ 5.25 V		0.6		mV
	Drift		IOUT = 0		36		PPM/°C
DIGIT	AL INPUT/OUTPUT						
	Logic family — CMOS						
V_{IH}	High level input voltage		$I_{IH} = 5 \mu A$	+VBD - 1		+VBD + 0.3	
V_{IL}	Low level input voltage		$I_{IL} = 5 \mu A$	-0.3		0.8	V
V_{OH}	High level output voltage		I _{OH} = 2 TTL loads	+VBD - 0.6		+VBD	V
V _{OL}	Low level output voltage		I _{OL} = 2 TTL loads	0		0.4	
	Data format – 2's comple	ment					
POWE	R SUPPLY REQUIREMENT	S					
	D	+VBD		2.7	3	5.25	V
	Power supply voltage	+VA		4.75	5	5.25	V
	+VA Supply current(8)	•	f _s = 2 MHz		35	40	mA
P_D	Power dissipation ⁽⁸⁾		f _s = 2 MHz		175	200	mW
TEMP	ERATURE RANGE		<u> </u>				
T _A	Operating free-air			-40		85	°C

Can vary $\pm 20\%$ This includes only +VA current. +VBD current is typically 1 mA with 5-pF load capacitance on output pins.



TIMING CHARACTERISTICS

All specifications typical at -40° C to 85° C, $+VA = +VBD = 5 V^{(1)(2)(3)}$

	PARAMETER	MIN	TYP MAX	UNIT
CONV	Conversion time	340	400	ns
ACQ	Acquisition time	100		ns
pd1	CONVST low to BUSY high		30	ns
pd2	Propagation delay time, end of conversion to BUSY low		5	ns
w1	Pulse duration, CONVST low	20		ns
su1	Setup time, $\overline{\text{CS}}$ low to $\overline{\text{CONVST}}$ low	0		ns
w2	Pulse duration, CONVST high	20		ns
	CONVST falling edge jitter		10	ps
w3	Pulse duration, BUSY signal low	Min(t _{ACQ})		ns
v4	Pulse duration, BUSY signal high		370	ns
ո1	Hold time, first data bus data transition (RD low, or CS low for read cycle, or BYTE input changes) after CONVST low	40		ns
11	Delay time, \overline{CS} low to \overline{RD} low (or BUSY low to \overline{RD} low)	0		ns
su2	Setup time, RD high to CS high	0		ns
w5	Pulse duration, RD low	50		ns
en	Enable time, RD low (or CS low for read cycle) to data valid		20	ns
2	Delay time, data hold from $\overline{\text{RD}}$ high	0		ns
13	Delay time, BYTE rising edge or falling edge to data valid	2	20	ns
v6	Pulse duration, RD high	20		ns
v7	Pulse duration, CS high	20		ns
12	Hold time, last $\overline{\text{RD}}$ (or $\overline{\text{CS}}$ for read cycle) rising edge to $\overline{\text{CONVST}}$ falling edge	50		ns
su3	Setup time, BYTE transition to RD falling edge	0		ns
13	Hold time, BYTE transition to RD falling edge	0		ns
lis	Disable time, RD high (CS high for read cycle) to 3-stated data bus		20	ns
15	Delay time, end of conversion to MSB data valid		10	ns
su4	Byte transition setup time, from BYTE transition to the next BYTE transition	50		ns
16	Delay time, CS rising edge to BUSY falling edge	50		ns
d7	Delay time, BUSY falling edge to CS rising edge	50		ns
su(AB)	Setup time, from the falling edge of CONVST (used to start the valid conversion) to the next falling edge of CONVST (when $\overline{CS} = 0$ and \overline{CONVST} used to abort) or to the next falling edge of \overline{CS} (when \overline{CS} is used to abort)	60	340	ns
su5	Setup time, falling edge of CONVST to read valid data (MSB) from current conversion	$MAX(t_{CONV}) + MAX(t_{d5})$		ns
n4	Hold time, data (MSB) from previous conversion hold valid from falling edge of CONVST		MIN(t _{CONV})	ns

⁽¹⁾ All input signals are specified with t_r = t_f = 5 ns (10% to 90% of +VBD) and timed from a voltage level of (V_{IL} + V_{IH})/2. (2) See timing diagrams.

⁽²⁾ See timing diagrams.(3) All timings are measured with 20 pF equivalent loads on all data bits and BUSY pins.



TIMING CHARACTERISTICS

All specifications typical at -40° C to 85°C, +VA = 5 V, +VBD = 3 V $^{(1)(2)(3)}$

	PARAMETER	MIN	TYP MAX	UNIT
t_{CONV}	Conversion time	340	400	ns
t _{ACQ}	Acquisition time	100		ns
t _{pd1}	CONVST low to conversion started (BUSY high)		40	ns
t _{pd2}	Propagation delay time, end of conversion to BUSY low		10	ns
t _{w1}	Pulse duration, CONVST low	20		ns
t _{su1}	Setup time, CS low to CONVST low	0		ns
t _{w2}	Pulse duration, CONVST high	20		ns
	CONVST falling edge jitter		10	ps
t _{w3}	Pulse duration, BUSY signal low	Min(t _{ACQ})		ns
t _{w4}	Pulse duration, BUSY signal high		370	ns
t _{h1}	Hold time, first data bus transition (RD low, or CS low for read cycle, or BYTE input changes) after CONVST low	40		ns
t _{d1}	Delay time, \overline{CS} low to \overline{RD} low (or BUSY low to \overline{RD} low)	0		ns
t _{su2}	Setup time, RD high to CS high	0		ns
t _{w5}	Pulse duration, RD low	50		ns
t _{en}	Enable time, $\overline{\text{RD}}$ low (or $\overline{\text{CS}}$ low for read cycle) to data valid		30	ns
t _{d2}	Delay time, data hold from RD high	0		ns
t _{d3}	Delay time, BYTE rising edge or falling edge to data valid	2	30	ns
t _{w6}	Pulse duration, RD high	20		ns
t _{w7}	Pulse duration, CS high	20		ns
t _{h2}	Hold time, last $\overline{\text{RD}}$ (or $\overline{\text{CS}}$ for read cycle) rising edge to $\overline{\text{CONVST}}$ falling edge	50		ns
t _{su3}	Setup time, BYTE transition to RD falling edge	0		ns
t _{h3}	Hold time, BYTE transition to RD falling edge	0		ns
t _{dis}	Disable time, RD high (CS high for read cycle) to 3-stated data bus		30	ns
t _{d5}	Delay time, end of conversion to MSB data valid		20	ns
t _{su4}	Byte transition setup time, from BYTE transition to next BYTE transition	50		ns
t _{d6}	Delay time, CS rising edge to BUSY falling edge	50		ns
t _{d7}	Delay time, BUSY falling edge to $\overline{\text{CS}}$ rising edge	50		ns
t _{su(AB)}	Setup time, from the falling edge of CONVST (used to start the valid conversion) to the next falling edge of CONVST (when $\overline{CS} = 0$ and \overline{CONVST} used to abort) or to the next falling edge of \overline{CS} (when \overline{CS} is used to abort)	70	350	ns
t _{su5}	Setup time, falling edge of CONVST to read valid data (MSB) from current conversion	$MAX(t_{CONV}) + MAX(t_{d5})$		ns
t _{h4}	Hold time, data (MSB) from previous conversion hold valid from falling edge of CONVST		MIN(t _{CONV})	ns

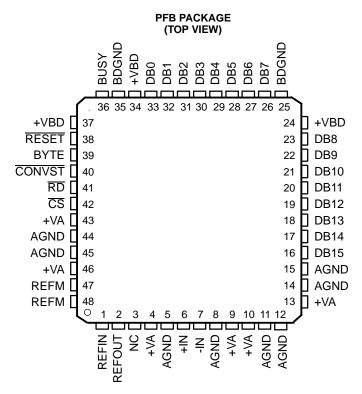
All input signals are specified with $t_r = t_f = 5$ ns (10% to 90% of +VBD) and timed from a voltage level of $(V_{IL} + V_{IH})/2$. See timing diagrams.

⁽²⁾ (3)

All timings are measured with 20 pF equivalent loads on all data bits and BUSY pins.



PIN ASSIGNMENTS



NC - No connection

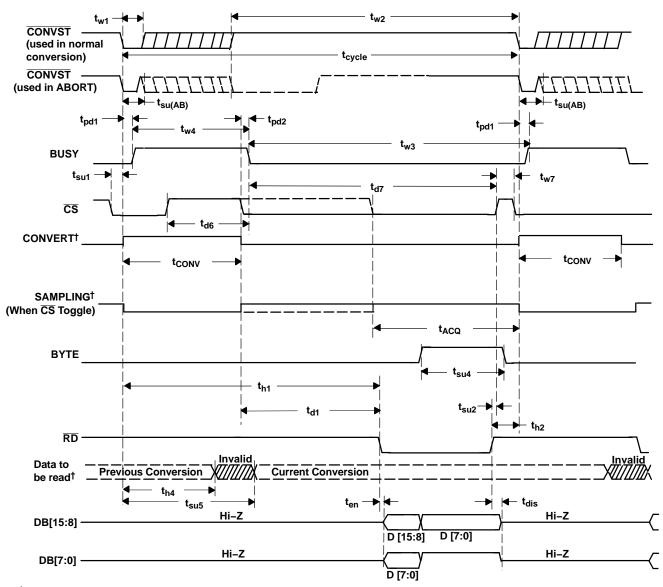


Terminal Functions

NAME	NO.	I/O		DESCRIPTION				
AGND	5, 8, 11, 12, 14, 15, 44, 45	-	Analog ground					
BDGND	25, 35	-	Digital ground for bus interface dig	gital supply				
BUSY	36	0	Status output. High when a conve	rsion is in progress.				
BYTE	39	I		us reading. 0: No fold back 1: Low b gh byte of the 16 most significant pi				
CONVST	40	I	Convert start. The falling edge of	his input ends the acquisition perio	d and starts the hold period.			
CS	42	I	Chip select. The falling edge of the	s input starts the acquisition period				
Data Bus			8-Bi	t Bus	16-Bit Bus			
Dala Dus			BYTE = 0	BYTE = 1	BYTE = 0			
DB15	16	0	D15 (MSB)	D7	D15 (MSB)			
DB14	17	0	D14	D6	D14			
DB13	18	0	D13	D5	D13			
DB12	19	0	D12	D4	D12			
DB11	20	0	D11	D3	D11			
DB10	21	0	D10	D2	D10			
DB9	22	0	D9	D1	D9			
DB8	23	0	D8	D0 (LSB)	D8			
DB7	26	0	D7	All ones	D7			
DB6	27	0	D6	All ones	D6			
DB5	28	0	D5	All ones	D5			
DB4	29	0	D4	All ones	D4			
DB3	30	0	D3	All ones	D3			
DB2	31	0	D2	All ones	D2			
DB1	32	0	D1	All ones	D1			
DB0	33	0	D0 (LSB)	All ones	D0 (LSB)			
-IN	7	I	Inverting input channel	l.				
+IN	6	I	Non inverting input channel					
NC	3	-	No connection					
REFIN	1	I	Reference input					
REFM	47, 48	I	Reference ground					
REFOUT	2	0	Reference output. Add 1 µF capacitor between the REFOUT pin and REFM pin when internal reference is used.					
RESET	38	I	Current conversion is aborted and output latches are cleared (set to zeros) when this pin is asserted low. RESET works independently of CS.					
RD	41	I	Synchronization pulse for the parallel output. When $\overline{\text{CS}}$ is low, this serves as the output enable and puts the previous conversion result on the bus.					
+VA	4, 9, 10, 13, 43, 46	-	Analog power supplies, 5-V dc					
+VBD	24, 34, 37	-	Digital power supply for bus					



TIMING DIAGRAMS



[†]Signal internal to device

Figure 1. Timing for Conversion and Acquisition Cycles With CS and RD Toggling



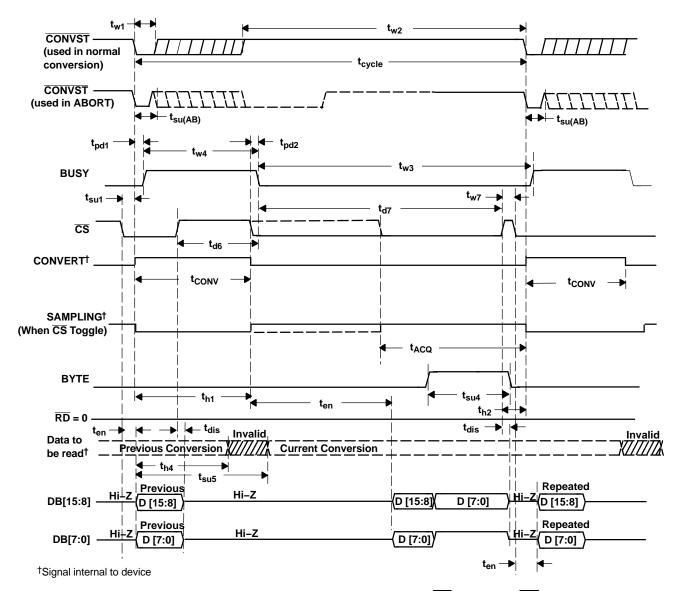


Figure 2. Timing for Conversion and Acquisition Cycles With $\overline{\text{CS}}$ Toggling, $\overline{\text{RD}}$ Tied to BDGND



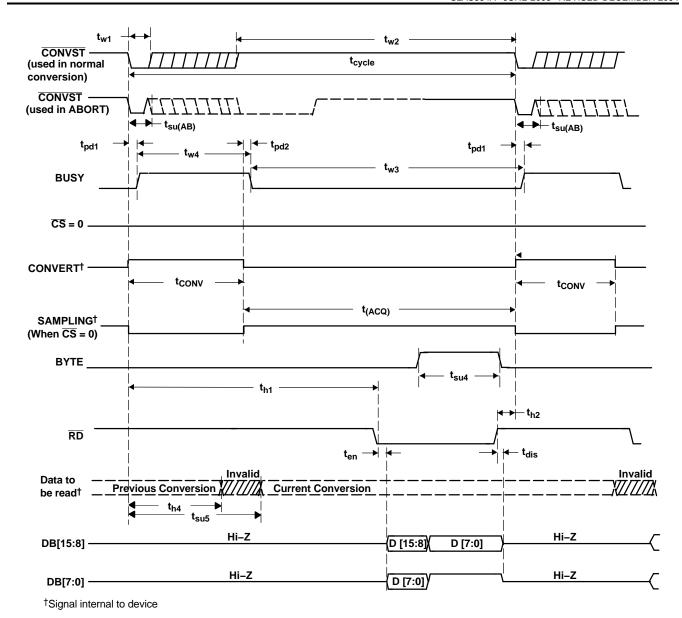
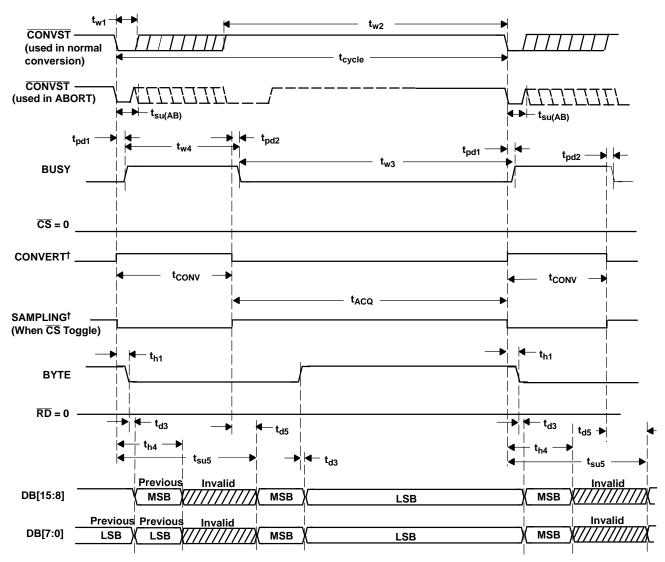


Figure 3. Timing for Conversion and Acquisition Cycles With $\overline{\text{CS}}$ Tied to BDGND, $\overline{\text{RD}}$ Toggling





[†]Signal internal to device

Figure 4. Timing for Conversion and Acquisition Cycles With $\overline{\text{CS}}$ and $\overline{\text{RD}}$ Tied to BDGND—Auto Read

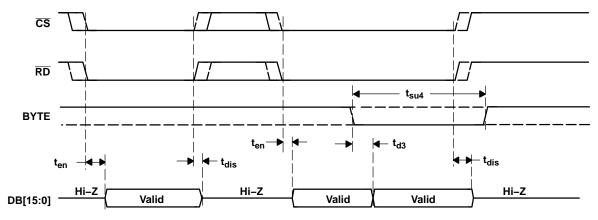
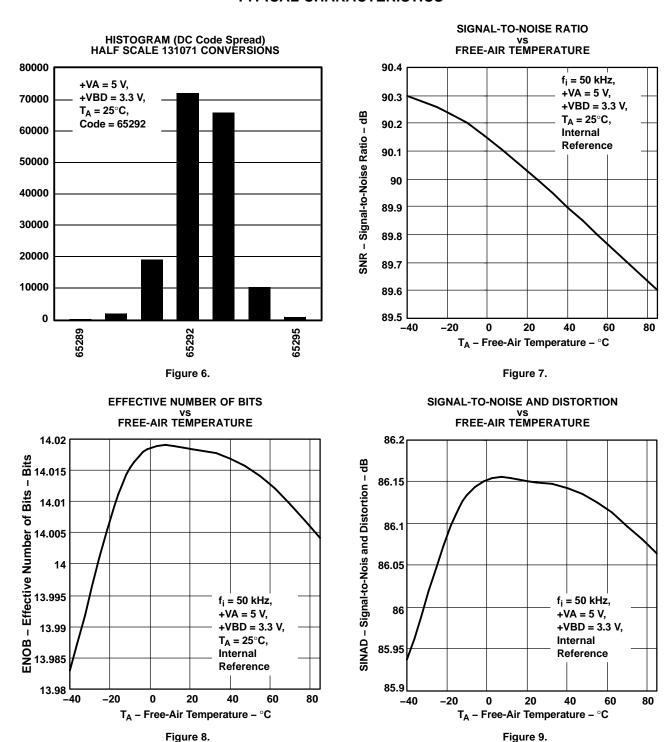


Figure 5. Detailed Timing for Read Cycles



TYPICAL CHARACTERISTICS



At -40° C to 85° C, +VA = 5 V, +VBD = 5 V, REFIN = 4.096 V (internal reference used) and f_{sample} = 2 MHz (unless otherwise noted)



SPURIOUS FREE DYNAMIC RANGE

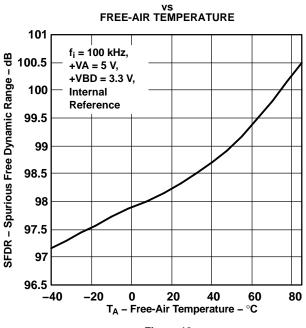


Figure 10.

SIGNAL-TO-NOISE RATIO

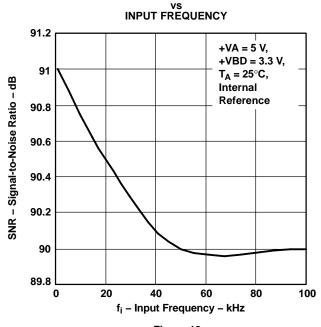


Figure 12.

TOTAL HARMONIC DISTORTION vs FREE-AIR TEMPERATURE

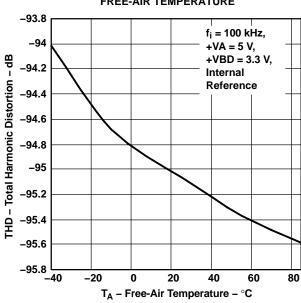


Figure 11.

EFFECTIVE NUMBER OF BITS vs INPUT FREQUENCY

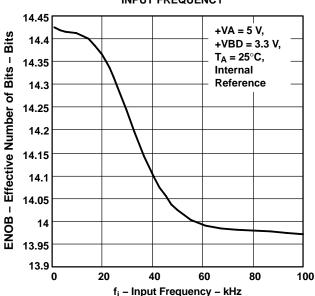
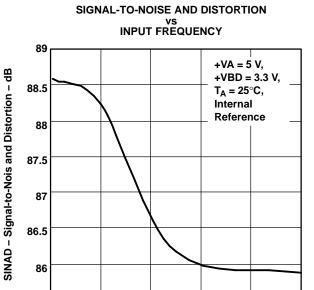


Figure 13.







85.5 o 20 100 f_i - Input Frequency - kHz

TOTAL HARMONIC DISTORTION vs INPUT FREQUENCY

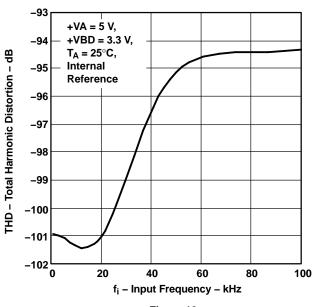


Figure 16.

SPURIOUS FREE DYNAMIC RANGE vs INPUT FREQUENCY

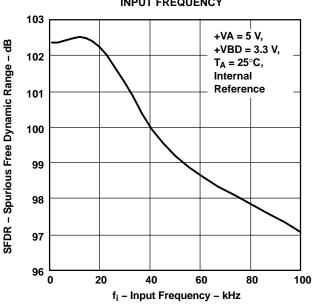


Figure 15.

SUPPLY CURRENT vs SAMPLE RATE

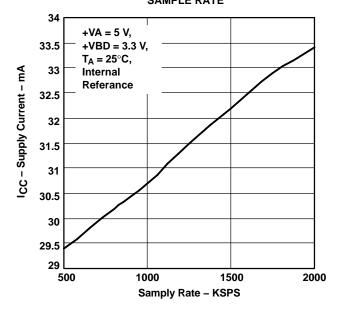
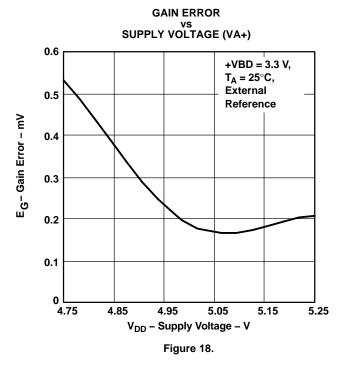
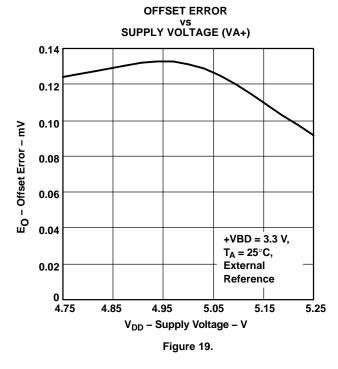


Figure 17.







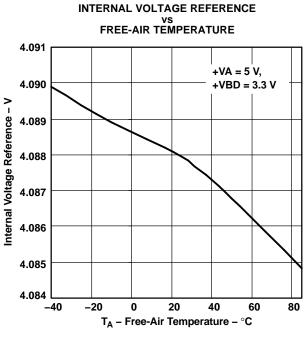
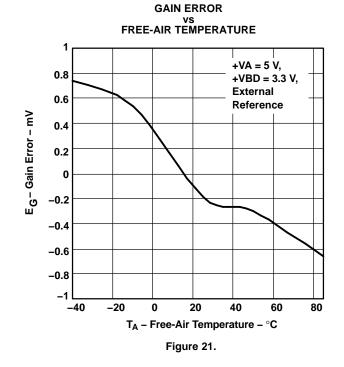
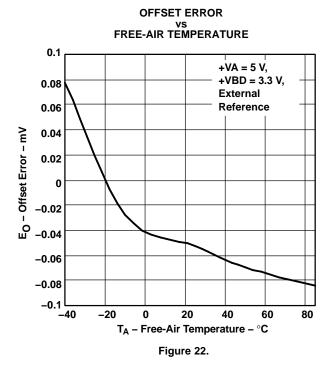
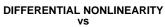


Figure 20.









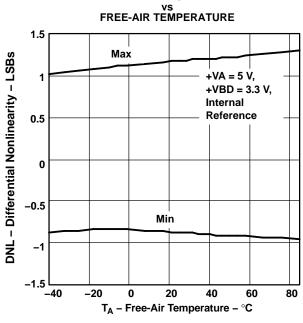


Figure 24.



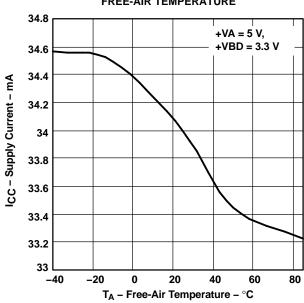


Figure 23.

INTEGRAL NONLINEARITY vs FREE-AIR TEMPERATURE

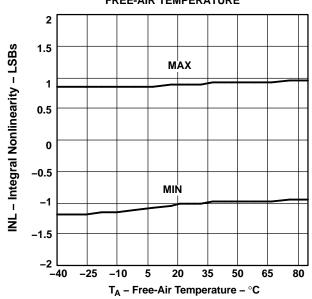
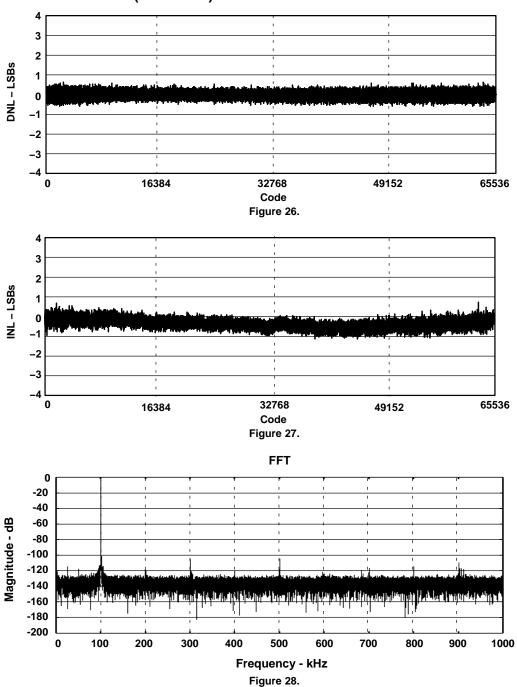


Figure 25.







APPLICATION INFORMATION

MICROCONTROLLER INTERFACING

ADS8412 to 8-Bit Microcontroller Interface

Figure 29 shows a parallel interface between the ADS8412 and a typical microcontroller using the 8-bit data bus. The BUSY signal is used as a falling-edge interrupt to the microcontroller.

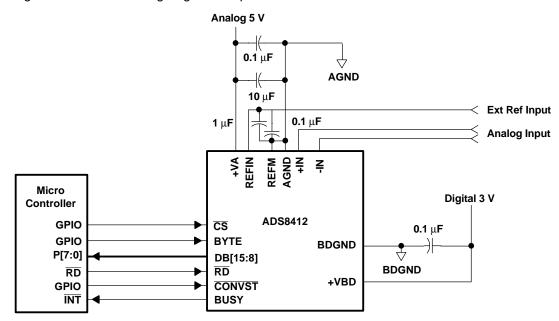


Figure 29. ADS8412 Application Circuitry (using external reference)

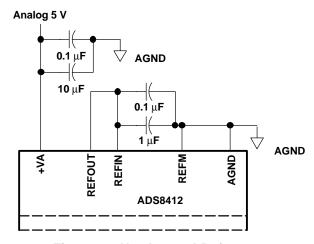


Figure 30. Use Internal Reference



PRINCIPLES OF OPERATION

The ADS8412 is a high-speed successive approximation register (SAR) analog-to-digital converter (ADC). The architecture is based on charge redistribution, which inherently includes a sample/hold function. See Figure 29 for the application circuit for the ADS8412.

The conversion clock is generated internally. The conversion time of 400 ns is capable of sustaining a 2-MHz throughput.

The analog input is provided to two input pins: +IN and -IN. When a conversion is initiated, the differential input on these pins is sampled on the internal capacitor array. While a conversion is in progress, both inputs are disconnected from any internal function.

REFERENCE

The ADS8412 can operate with an external reference with a range from 3.9 V to 4.2 V. A 4.096-V internal reference is included. When internal reference is used, pin 2 (REFOUT) should be connected to pin 1 (REFIN) with an 0.1 μ F decoupling capacitor and 1 μ F storage capacitor between pin 2 (REFOUT) and pins 47 and 48 (REFM) (see Figure 33). The internal reference of the converter is double buffered. If an external reference is used, the second buffer provides isolation between the external reference and the CDAC. This buffer is also used to recharge all of the capacitors of the CDAC during conversion. Pin 2 (REFOUT) can be left unconnected (floating) if external reference is used.

ANALOG INPUT

When the converter enters the hold mode, the voltage difference between the +IN and -IN inputs is captured on the internal capacitor array. Both +IN and -IN input has a range of -0.2 V to V_{ref} + 0.2 V. The input span(+IN - (-IN)) is limited to $-V_{ref}$ to V_{ref} .

The input current on the analog inputs depends upon a number of factors: sample rate, input voltage, and source impedance. Essentially, the current into the ADS8412 charges the internal capacitor array during the sample period. After this capacitance has been fully charged, there is no further input current. The source of the analog input voltage must be able to charge the input capacitance (25 pF) to an 16-bit settling level within the acquisition time (100 ns) of the device. When the converter goes into the hold mode, the input impedance is greater than 1 GO

Care must be taken regarding the absolute analog input voltage. To maintain the linearity of the converter, the +IN and -IN inputs and the span (+IN - (-IN)) should be within the limits specified. Outside of these ranges, the converter's linearity may not meet specifications. To minimize noise, low bandwidth input signals with low-pass filters should be used.

Care should be taken to ensure that the output impedance of the sources driving +IN and -IN inputs are matched. If this is not observed, the two inputs could have different setting time. This may result in offset error, gain error and linearity error which varies with temperature and input voltage.

A typical input circuit using TI's THS4503 is shown Figure 31. Input from a single-ended source may be converted into differential signal for ADS8412 as shown in the figure. In case the source itself is differential then THS4503 may be used in differential input and differential output mode.



PRINCIPLES OF OPERATION (continued)

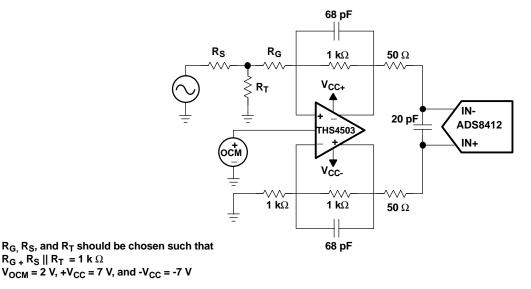


Figure 31. Using THS4503 With ADS8412

DIGITAL INTERFACE

Timing And Control

See the timing diagrams in the specifications section for detailed information on timing signals and their requirements.

The ADS8412 uses an internal oscillator generated clock which controls the conversion rate and in turn the throughput of the converter. No external clock input is required.

Conversions are initiated by bringing the $\overline{\text{CONVST}}$ pin low for a minimum of 20 ns (after the 20 ns minimum requirement has been met, the $\overline{\text{CONVST}}$ pin can be brought high), while $\overline{\text{CS}}$ is low. The ADS8412 switches from the sample to the hold mode on the falling edge of the $\overline{\text{CONVST}}$ command. A clean and low jitter falling edge of this signal is important to the performance of the converter. The BUSY output is brought high after $\overline{\text{CONVST}}$ goes low. BUSY stays high throughout the conversion process and returns low when the conversion has ended.

Sampling starts when \overline{CS} is tied low or starts with the falling edge of \overline{CS} when BUSY is low.

Both \overline{RD} and \overline{CS} can be high during and before a conversion with one exception (\overline{CS} must be low when \overline{CONVST} goes low to initiate a conversion). Both the \overline{RD} and \overline{CS} pins are brought low in order to enable the parallel output bus with the conversion.

Reading Data

The ADS8412 outputs full parallel data in two's complement format as shown in Table 1. The parallel output is active when \overline{CS} and \overline{RD} are both low. There is a minimal quiet zone requirement around the falling edge of \overline{CONVST} . This is 50 ns prior to the falling edge of \overline{CONVST} and 40 ns after the falling edge. No data read should be attempted within this zone. Any other combination of \overline{CS} and \overline{RD} sets the parallel output to 3-state. BYTE is used for multiword read operations. BYTE is used whenever lower bits of the conversion result are output on the higher byte of the bus. Refer to Table 1 for ideal output codes.



Table 1. Ideal Input Voltages and Output Codes

DESCRIPTION	ANALOG VALUE	DIGITAL OUTPUT – TWOS COMPLEMENT			
DESCRIPTION	ANALOG VALUE	BINARY CODE	HEX CODE		
Full Scale Range	2(+V _{ref})				
Least significant bit (LSB)	2(+V _{ref})/65536				
+Full scale	(+V _{ref}) – 1 LSB	0111 1111 1111 1111	7FFF		
Midscale	0 V	0000 0000 0000 0000	0000		
Midscale – 1 LSB	0 V – 1 LSB	1111 1111 1111 1111	FFFF		
-Full scale	(-V _{ref})	1000 0000 0000 0000	8000		

The output data is a full 16-bit word (D15-D0) on DB15-DB0 pins (MSB-LSB) if BYTE is low.

The result may also be read on an 8-bit bus for convenience. This is done by using only pins DB15-DB8. In this case two reads are necessary: the first as before, leaving BYTE low and reading the 8 most significant bits on pins DB15-DB8, then bringing BYTE high. When BYTE is high, the low bits (D7-D0) appears on pins DB15-D8.

These multiword read operations can be done with multiple active RD (toggling) or with RD tied low for simplicity.

Table 2. Conversion Data Readout

BYTE	DATA READ OUT					
DIIE	DB15-DB8 Pins	DB7-DB0 Pins				
High	D7-D0	All one's				
Low	D15-D8	D7-D0				

RESET

RESET is an asynchronous active low input signal (that works independently of \overline{CS}). Minimum RESET low time is 25 ns. Current conversion will be aborted no later than 50 ns after the converter is in the reset mode. In addition, all output latches are cleared (set to zero's) after RESET. The converter goes back to normal operation mode no later than 20 ns after RESET input is brought high.

The converter starts the first sampling period 20 ns after the rising edge of RESET. Any sampling period except for the one immediately after a RESET is started with the falling edge of the previous BUSY signal or the falling edge of CS, whichever is later.

Another way to reset the device is through the use of the combination of \overline{CS} and \overline{CONVST} . This is useful when the dedicated \overline{RESET} pin is tied to the system reset but there is a need to abort only the conversion in a specific converter. Since the BUSY signal is held high during the conversion, either one of these conditions triggers an internal self-clear reset to the converter just the same as a reset via the dedicated \overline{RESET} pin. The reset does not have to be cleared as for the dedicated \overline{RESET} pin. A reset can be started with either of the two following steps.

- Issue a CONVST when CS is low and a conversion is in progress. The falling edge of CONVST must satisfy
 the timing as specified by the timing parameter t_{su(AB)} mentioned in the timing characteristics table to ensure
 a reset. The falling edge of CONVST starts a reset. Timing is the same as a reset using the dedicated
 RESET pin except the instance of the falling edge is replaced by the falling edge of CONVST.

POWER-ON INITIALIZATION

RESET is not required after power on. An internal power-on reset circuit generates the reset. To ensure that all of the registers are cleared, three conversion cycles must be given to the converter after power on.



LAYOUT

For optimum performance, care should be taken with the physical layout of the ADS8412 circuitry.

As the ADS8412 offers single-supply operation, it is often used in close proximity with digital logic, microcontrollers, microprocessors, and digital signal processors. The more digital logic present in the design and the higher the switching speed, the more difficult it is to achieve good performance from the converter.

The basic SAR architecture is sensitive to glitches or sudden changes on the power supply, reference, ground connections and digital inputs that occur just prior to latching the output of the analog comparator. Thus, driving any single conversion for an n-bit SAR converter, there are at least n *windows* in which large external transient voltages can affect the conversion result. Such glitches might originate from switching power supplies, nearby digital logic, or high power devices.

The degree of error in the digital output depends on the reference voltage, layout, and the exact timing of the external event.

On average, the ADS8412 draws very little current from an external reference, as the reference voltage is internally buffered. If the reference voltage is external and originates from an op amp, make sure that it can drive the bypass capacitor or capacitors without oscillation. A 0.1-µF bypass capacitor and 1-µF storage capacitor are recommended from pin 1 (REFIN) directly to pin 48 (REFM). REFM and AGND should be shorted on the same ground plane under the device.

The AGND and BDGND pins should be connected to a clean ground point. In all cases, this should be the analog ground. Avoid connections which are close to the grounding point of a microcontroller or digital signal processor. If required, run a ground trace directly from the converter to the power supply entry point. The ideal layout consists of an analog ground plane dedicated to the converter and associated analog circuitry.

As with the AGND connections, +VA should be connected to a 5-V power supply plane or trace that is separate from the connection for digital logic until they are connected at the power entry point. Power to the ADS8412 should be clean and well bypassed. A 0.1-µF ceramic bypass capacitor should be placed as close to the device as possible. See Table 3 for the placement of the capacitor. In addition, a 1-µF to 10-µF capacitor is recommended. In some situations, additional bypassing may be required, such as a 100-µF electrolytic capacitor or even a Pi filter made up of inductors and capacitors—all designed to essentially low-pass filter the 5-V supply, removing the high frequency noise.

Table 3. Power Supply Decoupling Capacitor Placement

POWER SUPPLY PLANE SUPPLY PINS	CONVERTER ANALOG SIDE	CONVERTER DIGITAL SIDE
Pin pairs that require shortest path to decoupling capacitors	(4,5), (8,9), (10,11), (13,15), (43,44), (45,46)	(24,25), (34, 35)
Pins that require no decoupling	12, 14	37





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PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/ Ball Finish	MSL Peak Temp ⁽³⁾	Samples (Requires Login)
ADS8412IBPFBR	ACTIVE	TQFP	PFB	48	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	Purchase Samples
ADS8412IBPFBRG4	ACTIVE	TQFP	PFB	48	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	Purchase Samples
ADS8412IBPFBT	ACTIVE	TQFP	PFB	48	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	Request Free Samples
ADS8412IBPFBTG4	ACTIVE	TQFP	PFB	48	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	Request Free Samples
ADS8412IPFBT	ACTIVE	TQFP	PFB	48	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	Request Free Samples
ADS8412IPFBTG4	ACTIVE	TQFP	PFB	48	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	Request Free Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

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Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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Α	0	Dimension designed to accommodate the component width
В	0	Dimension designed to accommodate the component length
		Dimension designed to accommodate the component thickness
٧	٧	Overall width of the carrier tape
ГР	1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Paakaga	Pookogo	Dino	SPQ	Reel	Reel	Α0	В0	K0	P1	W	Pin1
Device	Type	Package Drawing		SFQ	Diameter		(mm)	(mm)	(mm)	(mm)		Quadrant
ADS8412IBPFBR	TQFP	PFB	48	1000	330.0	16.4	9.6	9.6	1.5	12.0	16.0	Q2
ADS8412IBPFBT	TQFP	PFB	48	250	330.0	16.4	9.6	9.6	1.5	12.0	16.0	Q2
ADS8412IPFBT	TQFP	PFB	48	250	330.0	16.4	9.6	9.6	1.5	12.0	16.0	Q2

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*All dimensions are nominal

7 till dilliteriererie dre riterininal							
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ADS8412IBPFBR	TQFP	PFB	48	1000	346.0	346.0	33.0
ADS8412IBPFBT	TQFP	PFB	48	250	346.0	346.0	33.0
ADS8412IPFBT	TQFP	PFB	48	250	346.0	346.0	33.0

PFB (S-PQFP-G48)

PLASTIC QUAD FLATPACK



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Falls within JEDEC MS-026

PFB (S-PQFP-G48)



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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